

# COMBINATIONAL ICs

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- REPRESENTATION OF BINARY VARIABLES AT THE PHYSICAL LEVEL
- BASIC SWITCH. STRUCTURE OF GATES AND THEIR OPERATION
- REALIZATION OF GATES USING CMOS CIRCUITS
- CHARACTERISTICS OF CIRCUITS: LOAD FACTORS AND FANOUT FACTORS, PROPAGATION DELAYS, TRANSITION TIMES, AND EFFECT OF LOAD
- THREE-STATE GATES (DRIVERS) AND BUSES
- NOISE AND NOISE MARGINS
- EVOLUTION OF ICs. VLSI CIRCUIT-LEVEL DESIGN STYLES
- PACKAGING LEVELS: CHIPS, BOARDS AND CABINETS.

## REPRESENTATION OF BINARY VARIABLES

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- REPRESENTATION OF 0 AND 1 BY ELECTRICAL SIGNALS
  - VOLTAGES
  - CURRENTS
  - ELECTRICAL CHARGES
- REALIZATION OF CIRCUITS THAT OPERATE ON THESE SIGNALS TO IMPLEMENT DESIRED SWITCHING FUNCTIONS

TYPICAL VALUES FOR A 3.3V CMOS TECHNOLOGY

$$V_{Hmax} \quad 3.3V \quad V_{Lmax} \quad 0.8V$$

$$V_{Hmin} \quad 2.0V \quad V_{Lmin} \quad 0.0V$$

# VOLTAGE REGIONS

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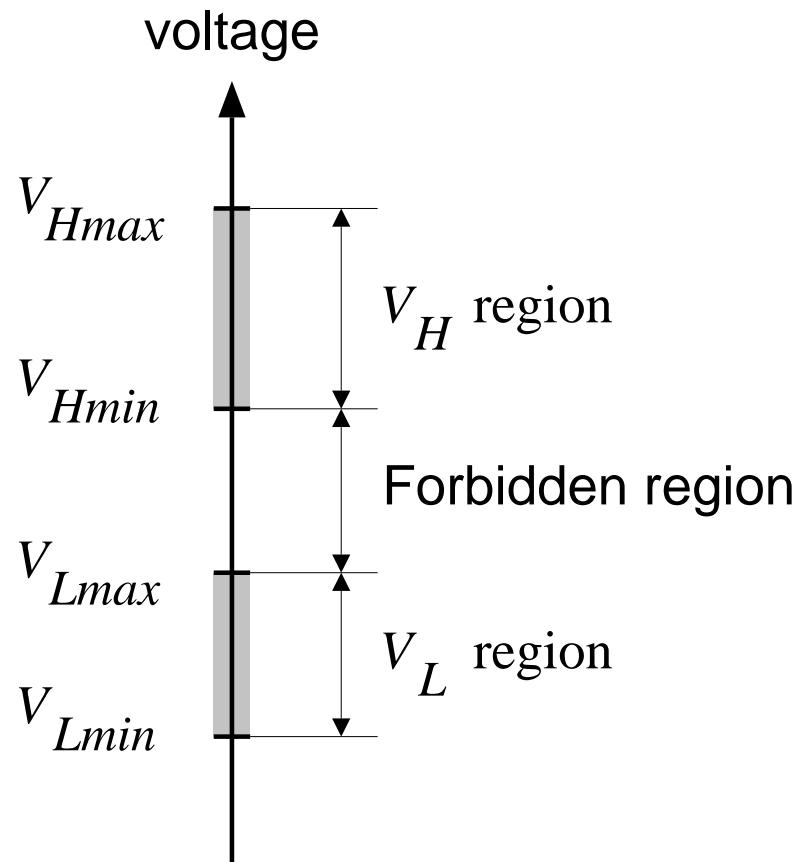
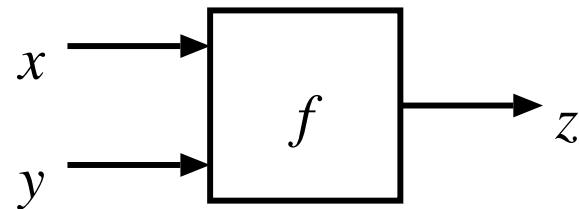


Figure 3.1: VOLTAGE REGIONS.

# POSITIVE AND NEGATIVE LOGIC

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*POSITIVE LOGIC*

$$V_H \longleftrightarrow 1$$

$$V_L \longleftrightarrow 0$$

*NEGATIVE LOGIC*

$$V_H \longleftrightarrow 0$$

$$V_L \longleftrightarrow 1$$

Input voltages		Output voltage	Positive logic			Negative logic		
$x$	$y$		$x$	$y$	$z$	$x$	$y$	$z$
$V_L$	$V_L$	$V_L$	0	0	0	1	1	1
$V_L$	$V_H$	$V_L$	0	1	0	1	0	1
$V_H$	$V_L$	$V_L$	1	0	0	0	1	1
$V_H$	$V_H$	$V_H$	1	1	1	0	0	0
			$f = \text{AND}$			$f = \text{OR}$		

# STRUCTURE AND OPERATION OF GATES

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## SWITCH AND MOS TRANSISTORS

### N-TYPE:

OPEN (OFF) if  $V_{CA} < V_{Tn}$

CLOSED (ON) if  $V_{CA} > V_{Tn}$

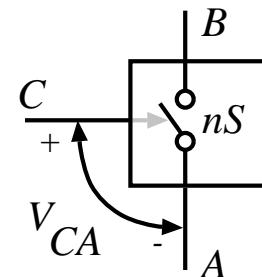
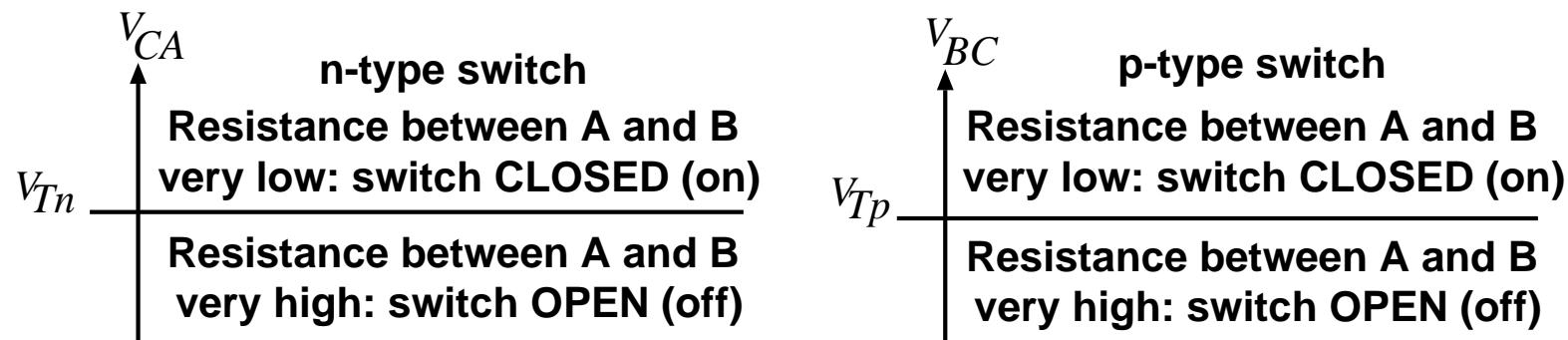
$V_{Tn}$  – THE THRESHOLD VOLTAGE FOR N-TYPE SWITCH

### P-TYPE:

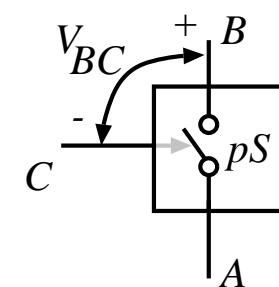
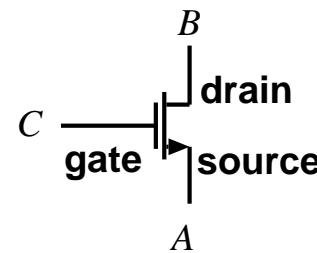
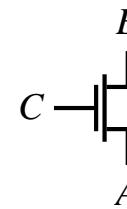
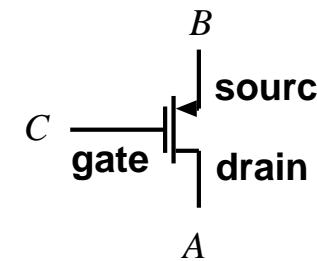
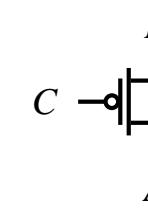
OPEN (OFF) if  $V_{BC} < V_{Tp}$

CLOSED (ON) if  $V_{BC} > V_{Tp}$

$V_{Tp}$  – THE THRESHOLD VOLTAGE FOR P-TYPE SWITCH



(a)

**NMOS transistor****logical symbol****PMOS transistor****logical symbol**

(b)

Figure 3.3: a) N-TYPE AND P-TYPE CONTROLLED SWITCHES. b) nMOS AND pMOS TRANSISTORS.

# CMOS NOT GATE

- COMPLEMENTARY MOS CIRCUIT

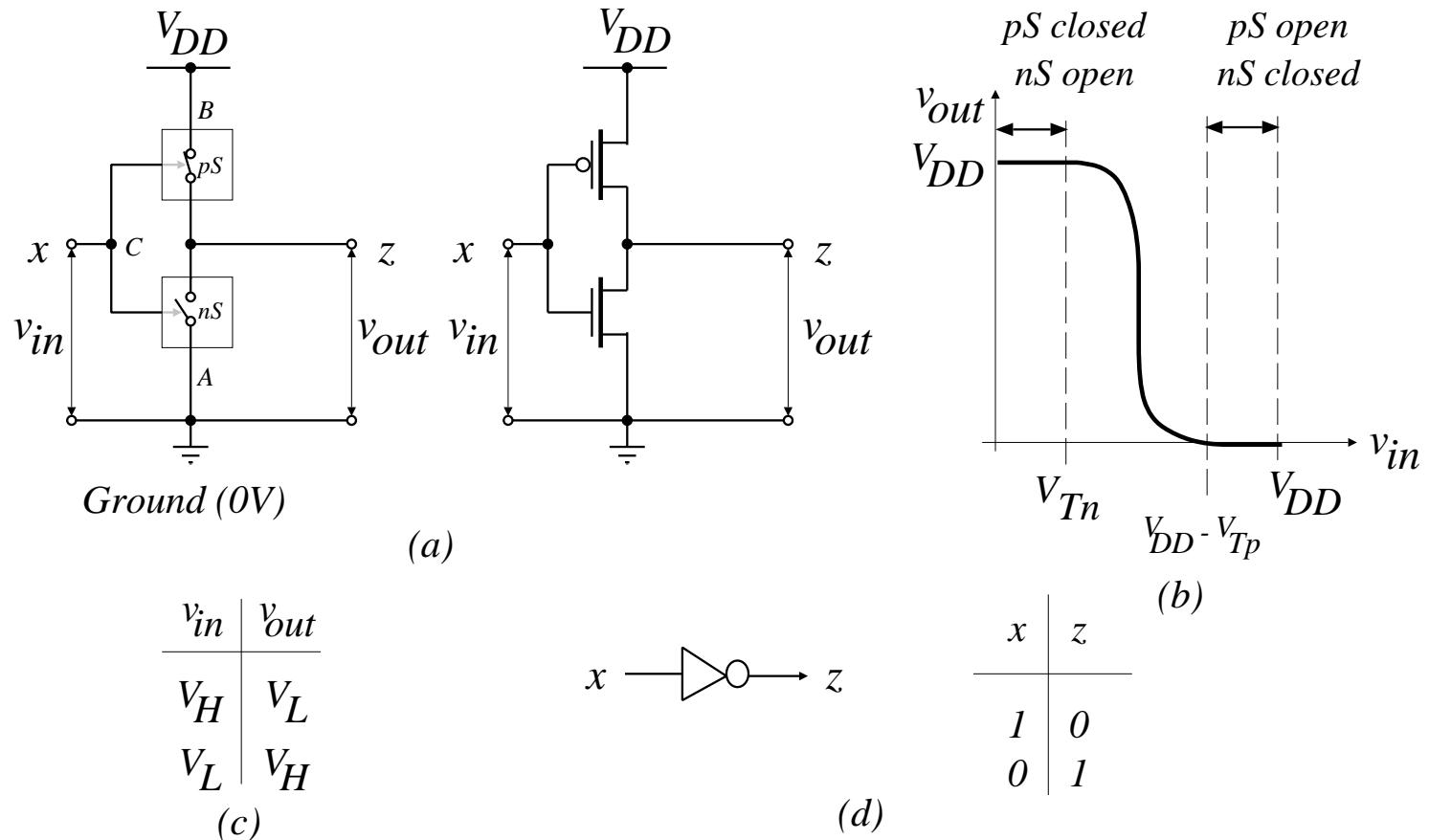


Figure 3.4: CIRCUIT, I/O CHARACTERISTIC, AND SYMBOL

## OPERATION OF NOT GATE

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$$V_{BC} = V_{DD} - v_{in} \quad (V_{DD} = V_{BC} + v_{in})$$

1.  $v_{in} < V_{Tn} \implies V_{CA} < V_{Tn}$

**N-SWITCH OPEN**

If  $V_{DD} > V_{Tn} + V_{Tp}$  then  $V_{BC} > V_{Tp}$

**P-SWITCH CLOSED AND  $v_{out} = V_{DD}$**

2.  $v_{in} > V_{DD} - V_{Tp} \implies V_{BC} < V_{Tp}$

**P-SWITCH IS OPEN**

If  $V_{DD} > V_{Tn} + V_{Tp}$  then  $V_{CA} > V_{Tn}$

**N-SWITCH IS CLOSED AND  $v_{out} = 0$**

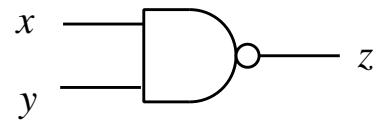
**CIRCUIT OPERATES AS NOT IF**

$$\begin{aligned} V_{Lmax} &< V_{Tn}, & V_{Hmin} &> V_{DD} - V_{Tp} \\ V_{DD} &> V_{Tn} + V_{Tp} \end{aligned}$$

# NAND and NOR GATES

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Circuit 1: NAND



Circuit 2: NOR

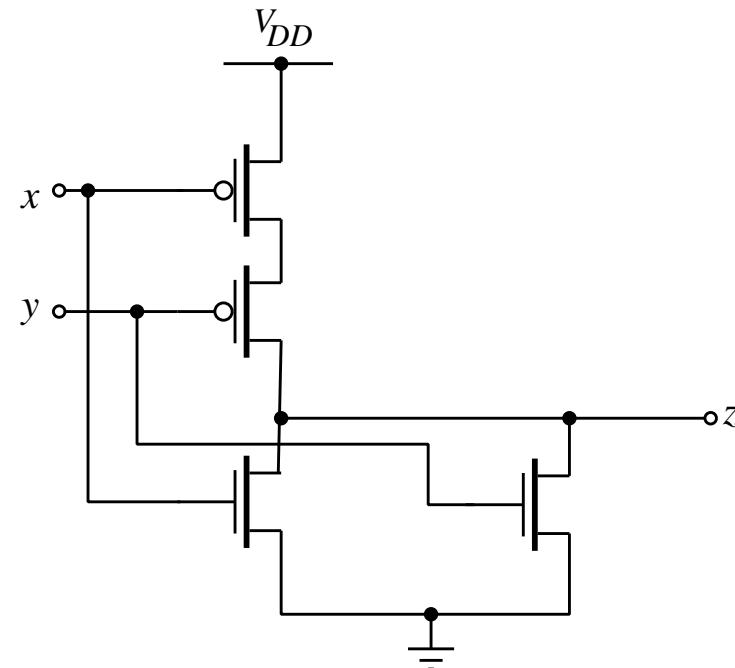
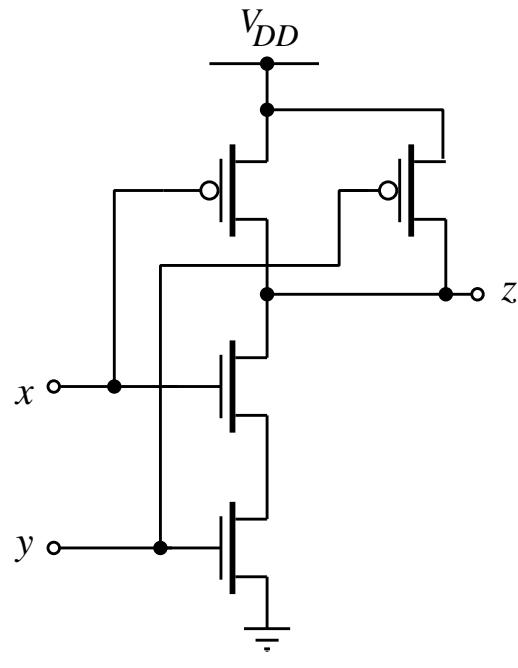
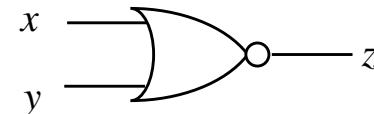


Figure 3.5: CIRCUITS FOR NAND and NOR GATES.

## NAND and NOR GATES (cont.)

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$x$	$y$	Circuit 1	Circuit 2
0	0	1	1
0	1	1	0
1	0	1	0
1	1	0	0

## AND and OR GATES

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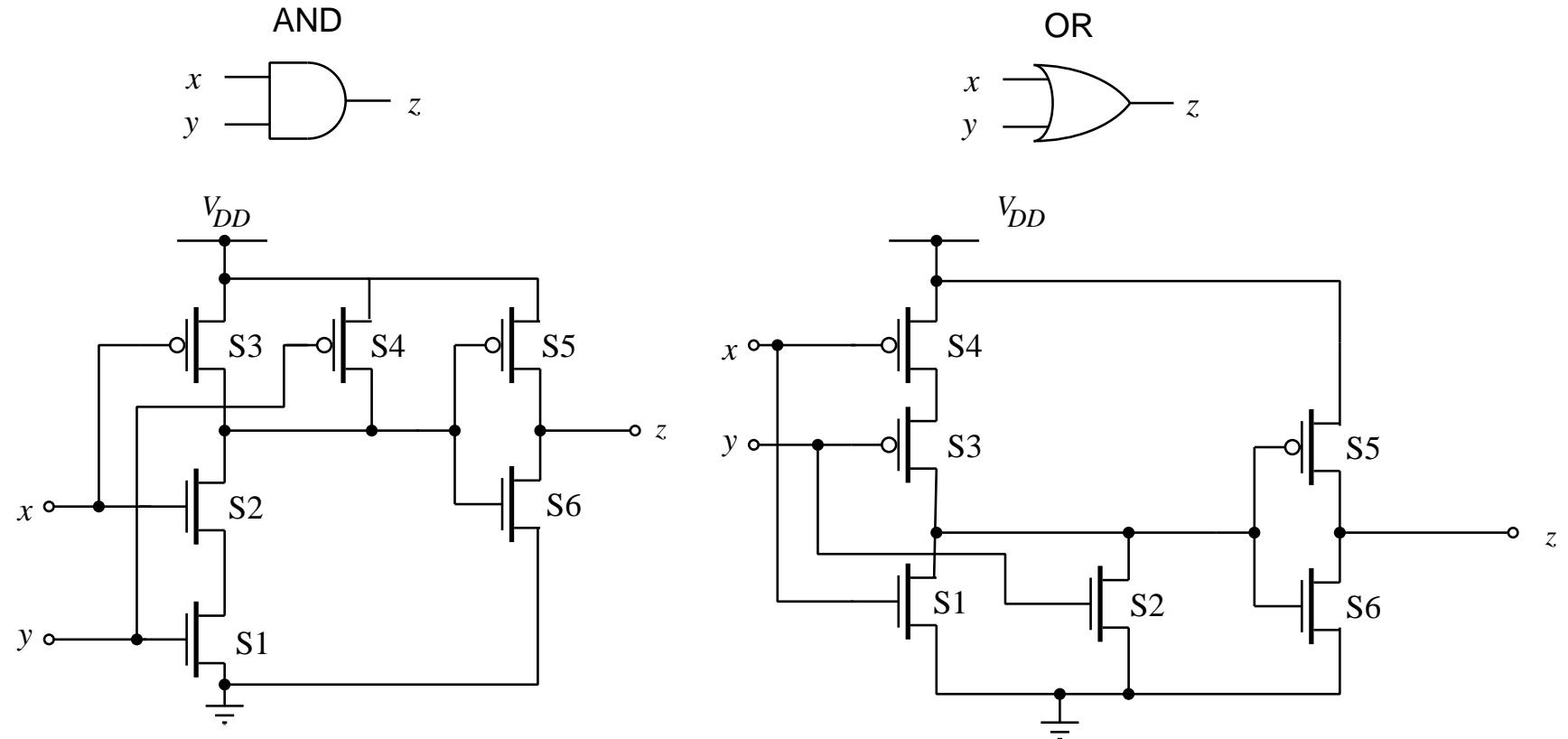
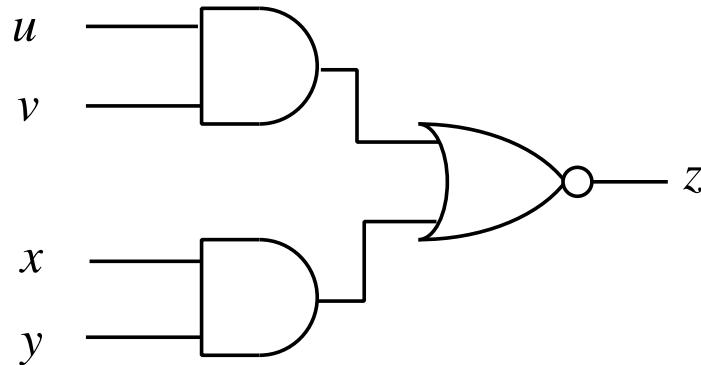


Figure 3.6: CIRCUITS FOR AND and OR GATES.

# COMPLEX GATES

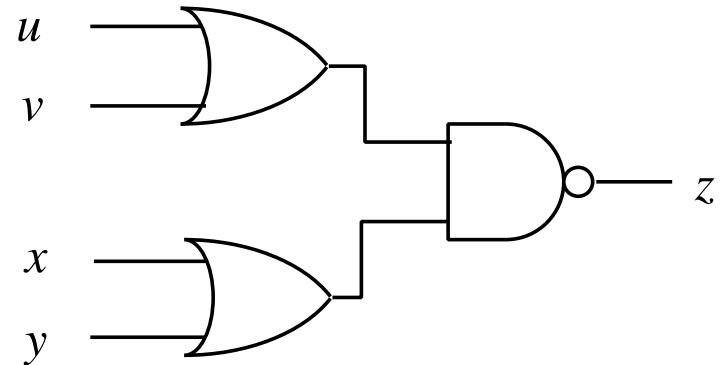
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**AND-OR-INVERT (AOI)**



$$z = (uv + xy)'$$

**OR-AND-INVERT (OAI)**



$$z = [(u+v)(x+y)]'$$

Figure 3.7: COMPLEX GATES.

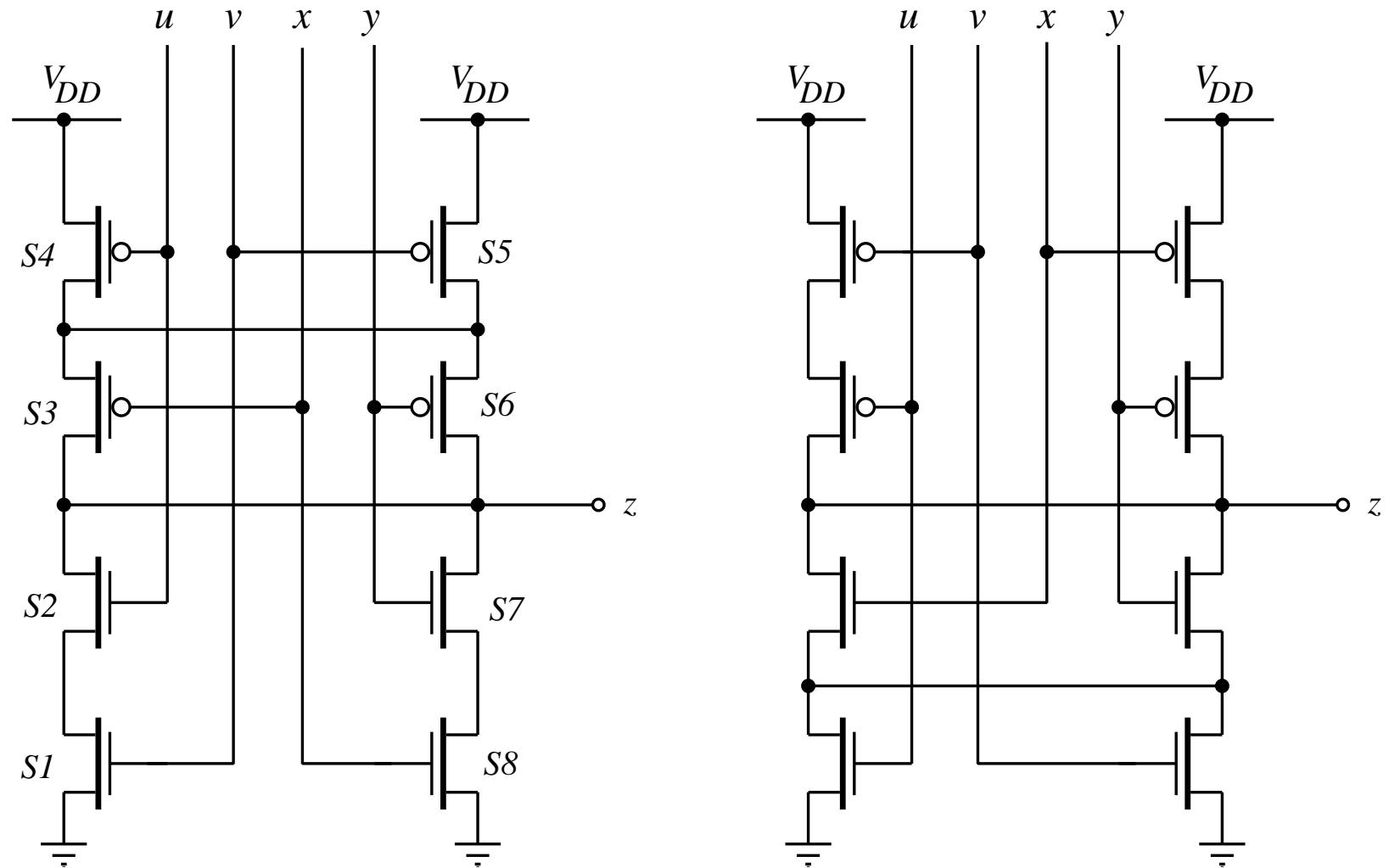
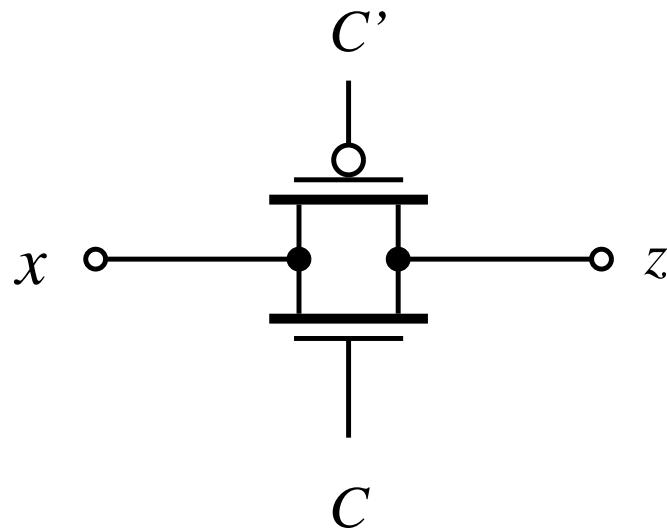


Figure 3.7: EXAMPLES OF COMPLEX GATES.

# TRANSMISSION GATE

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$C$	<i>n</i> -switch	<i>p</i> -switch	$z$
0	off	off	Z
1	on	on	x

*Z - high impedance state*

(a)

Figure 3.8: a) TRANSMISSION GATE

## XOR WITH TRANSMISSION GATES

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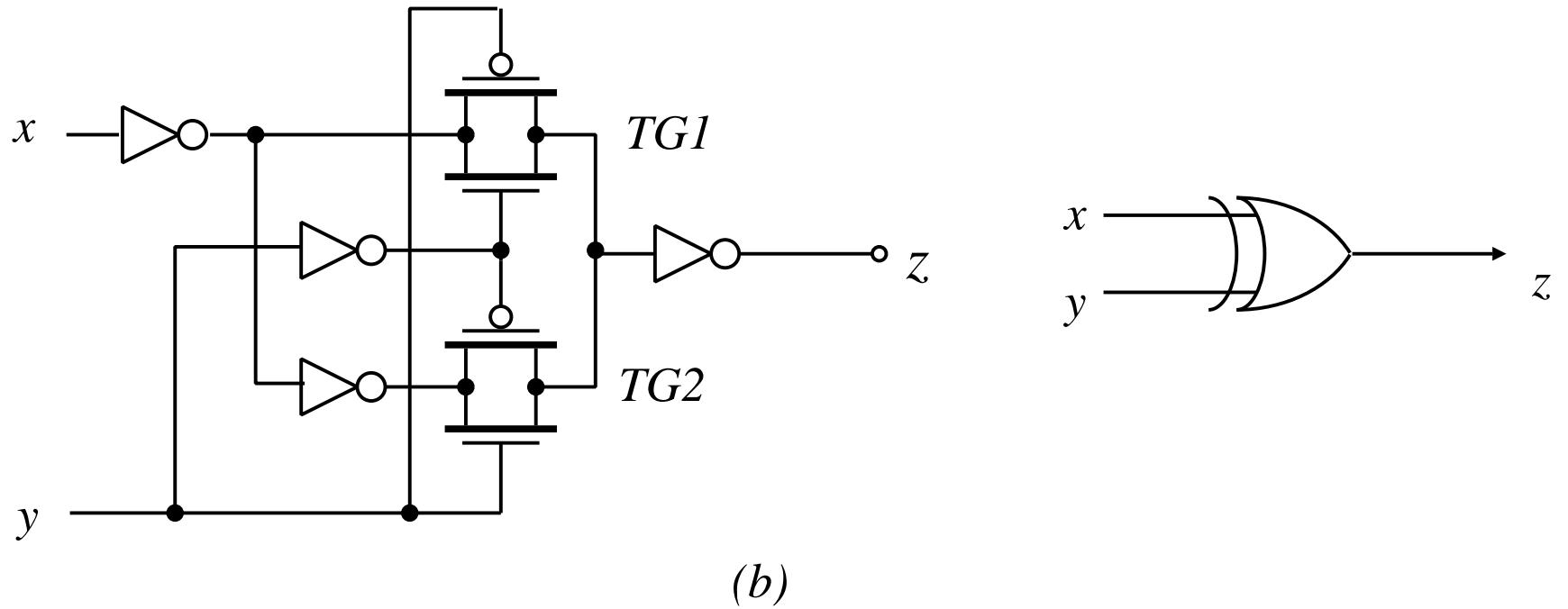
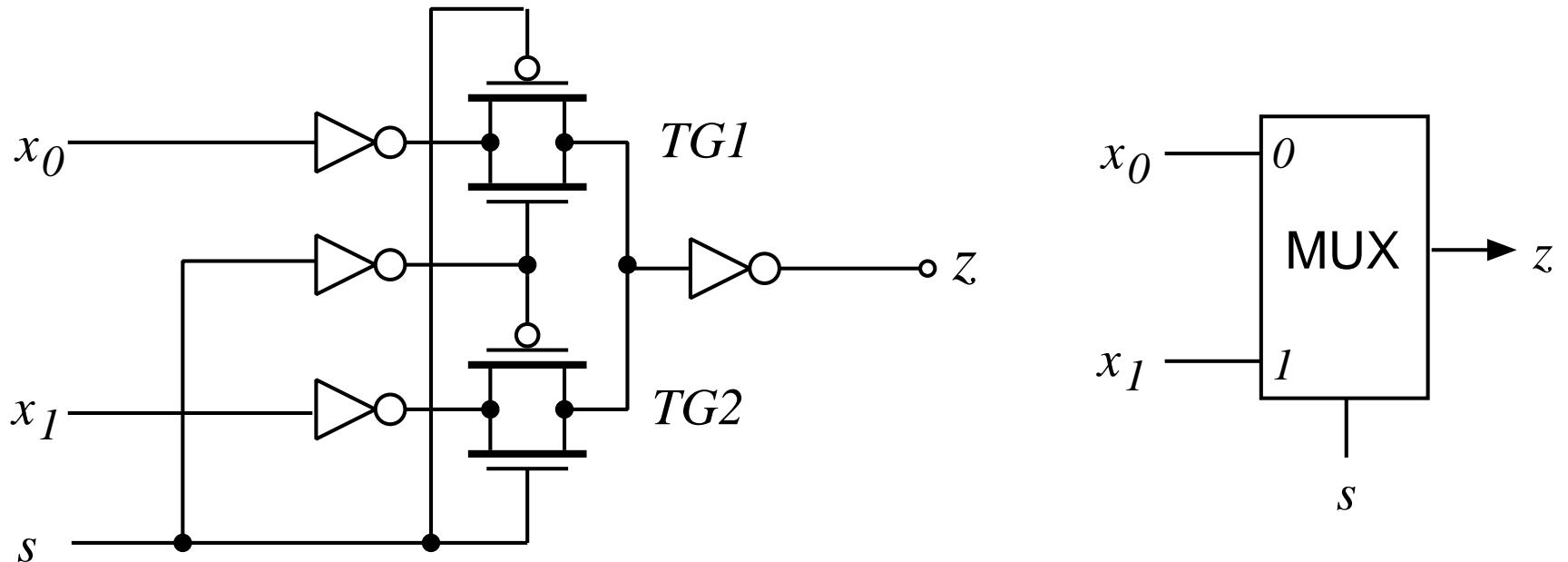


Figure 3.8: b) XOR GATE

$y$	$TG1$	$TG2$	$z$
0	ON	OFF	$x$
1	OFF	ON	$x'$

## MUX WITH TRANSMISSION GATES

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(c)

Figure 3.8: c) 2-INPUT MUX.

$$z = \text{MUX}(x_1, x_0, s) = x_1 s + x_0 s'$$

$s$	$TG1$	$TG2$	$z$
0	ON	OFF	$x_0$
1	OFF	ON	$x_1$

# TIMING PARAMETERS

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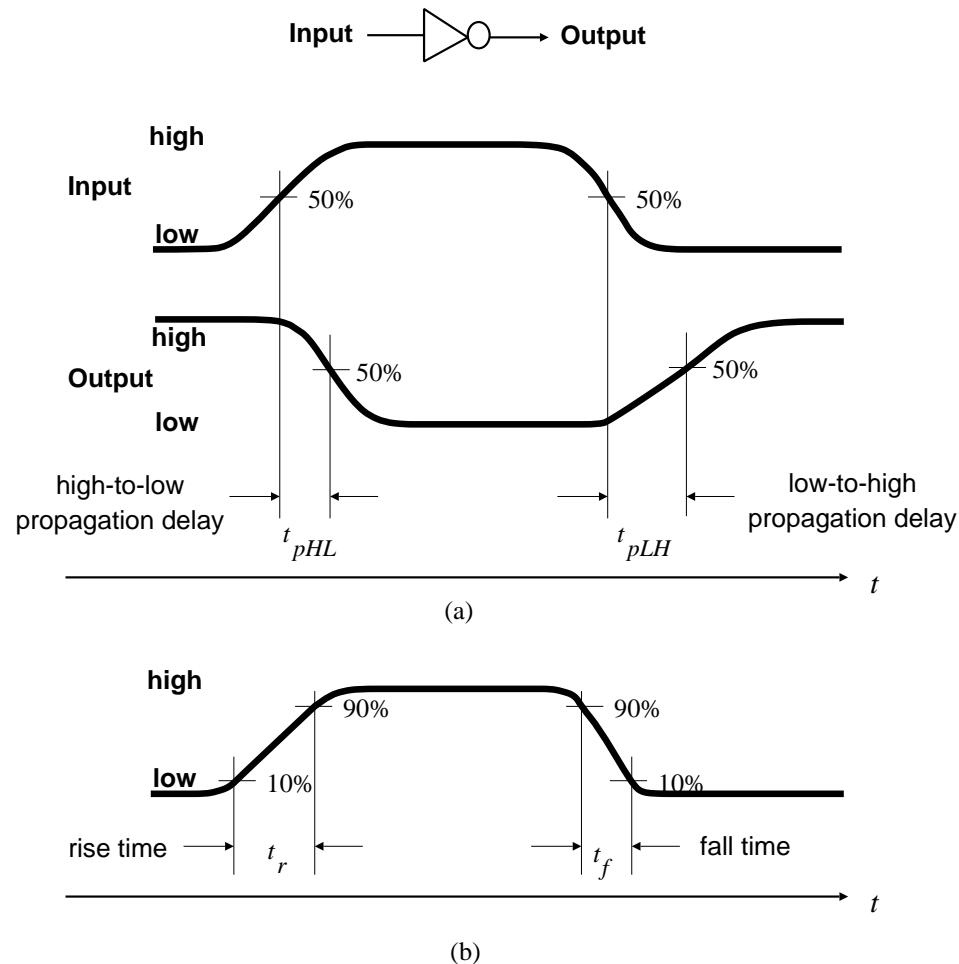


Figure 3.9: a) PROPAGATION DELAY. b) RISE AND FALL TIMES.

# EFFECT OF LOAD

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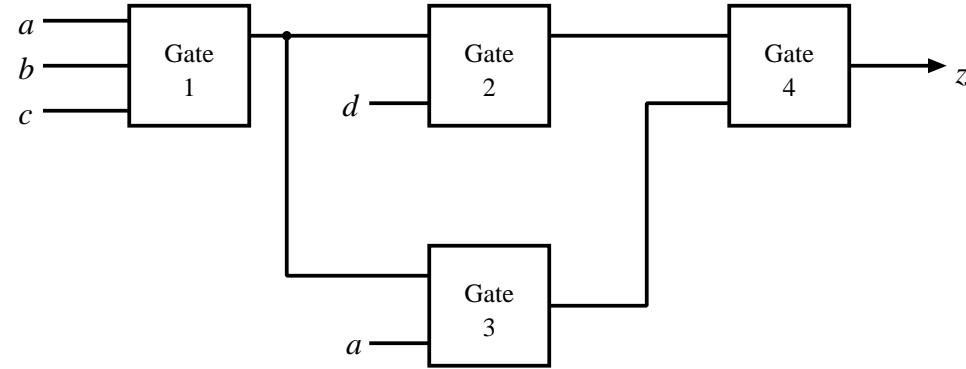


Figure 3.10: A GATE NETWORK

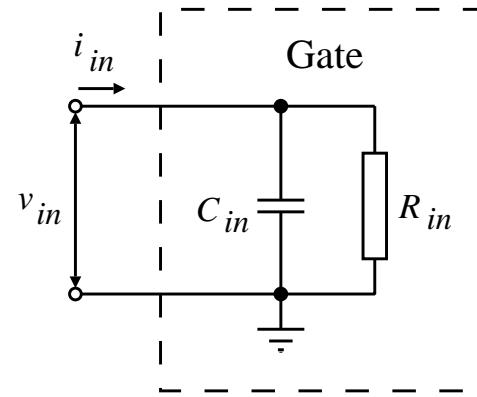


Figure 3.11: EQUIVALENT CIRCUIT FOR GATE INPUT.

## EFFECT OF LOAD ON PROPAGATION DELAY

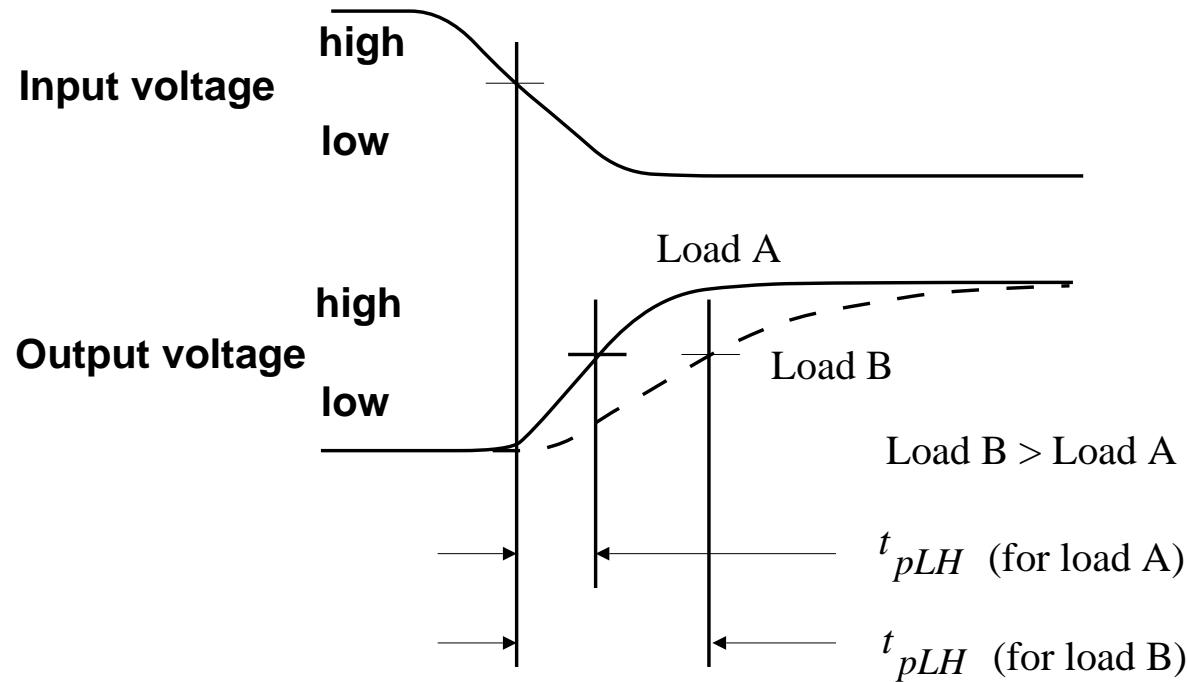


Figure 3.12: EFFECT OF LOAD ON PROPAGATION DELAY.

# LOAD FACTOR AND TOTAL LOAD

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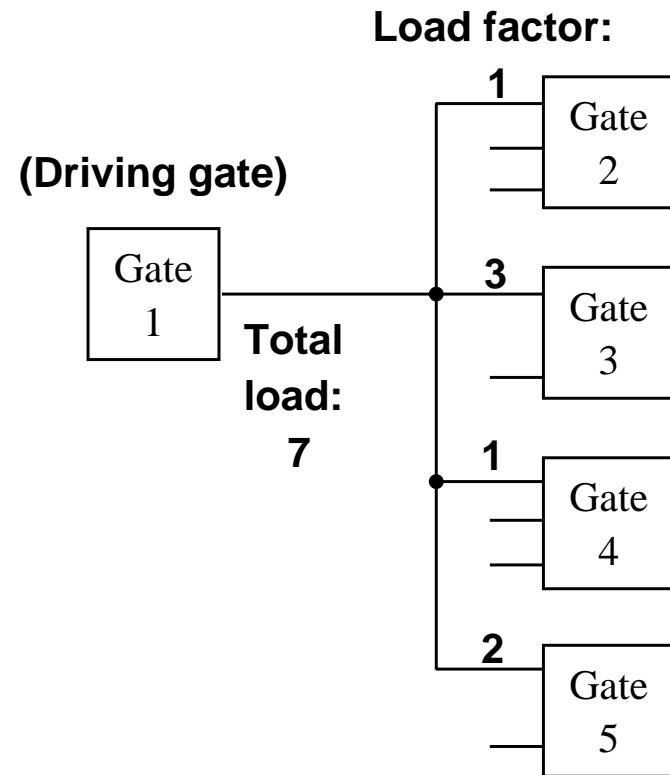


Figure 3.13: OUTPUT LOAD OF GATE 1.

## VOLTAGE VARIATIONS AND NOISE MARGINS

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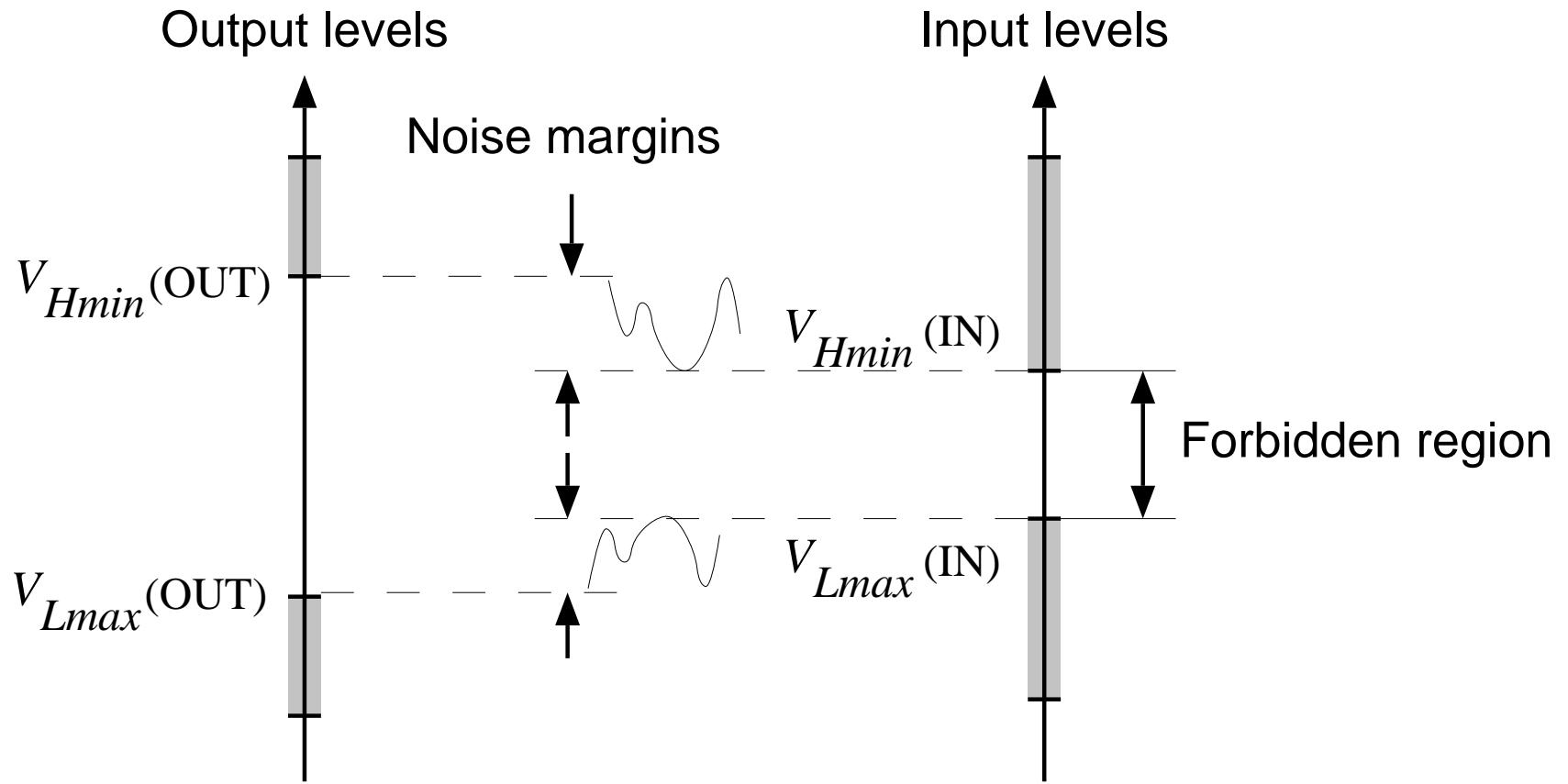


Figure 3.14: NOISE MARGINS.

## NOISE MARGINS: EXAMPLE

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LEVELS			NOISE MARGIN
HIGH	$V_{Hmin}(\text{OUT})$	2.4 V	0.4 V
	$V_{Hmin}(\text{IN})$	2.0 V	
LOW	$V_{Lmax}(\text{OUT})$	0.4 V	0.4 V
	$V_{Lmax}(\text{IN})$	0.8 V	

## CONNECTING MODULES TO A BUS

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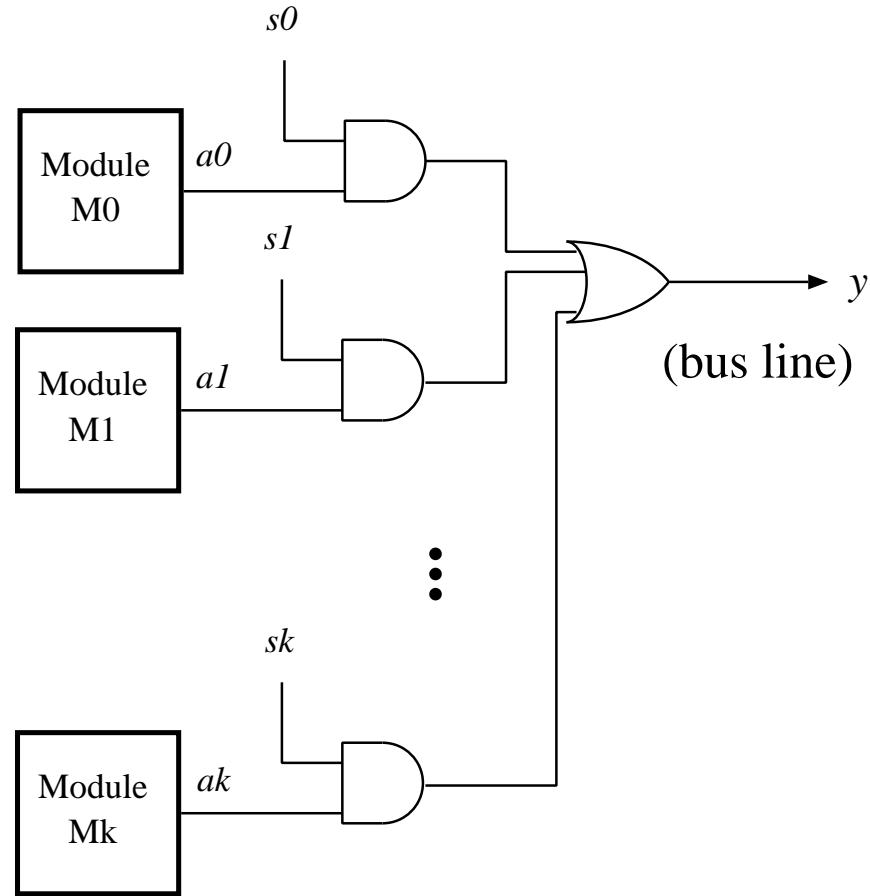


Figure 3.15: GATE NETWORK FOR SELECTING A MODULE OUTPUT.

## THREE-STATE DRIVER (BUFFER)

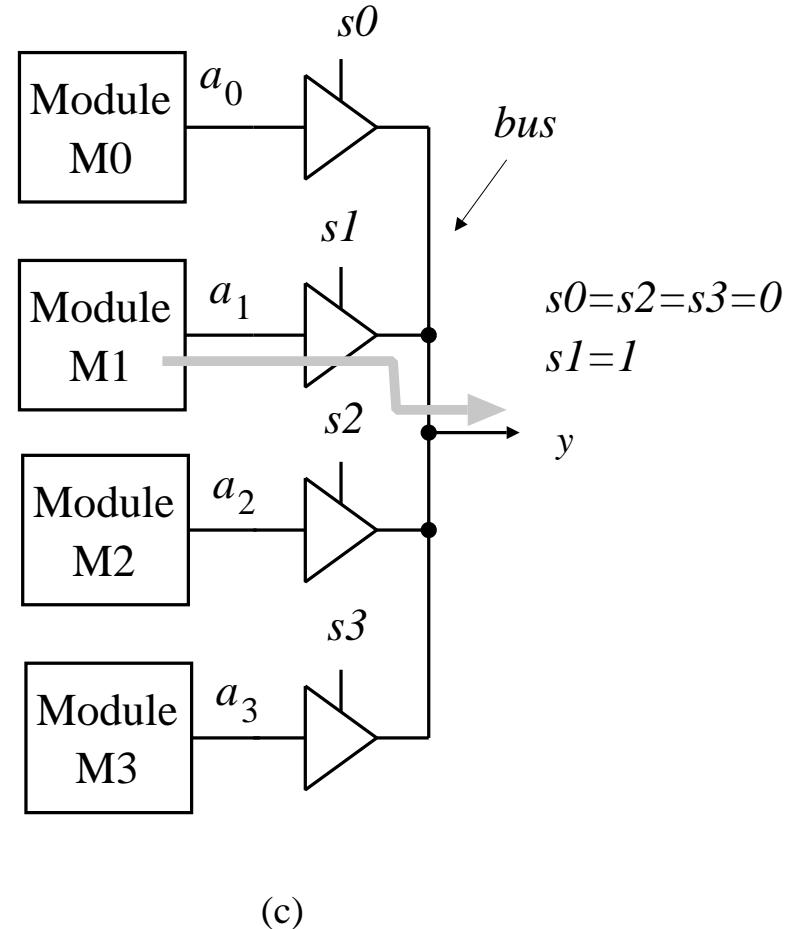
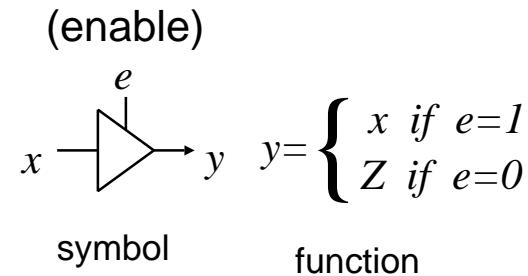
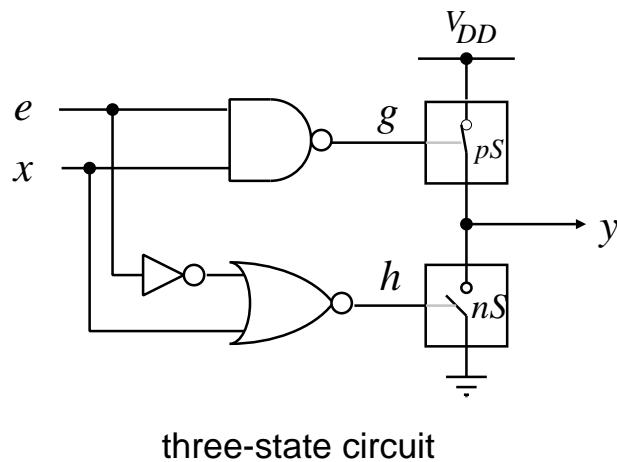


Figure 3.16: c) EXAMPLE OF USE OF THREE-STATE DRIVERS



(a)



$e$	$x$	$g$	$h$	$pS$	$nS$	$y$
0	0	1	0	open	open	Z
0	1	1	0	open	open	Z
1	0	1	1	open	closed	0
1	1	0	0	closed	open	1

three-state circuit operation

(b)

Figure 3.16: a) THREE-STATE GATE: SYMBOL AND FUNCTION. b) CIRCUIT AND OPERATION.

Table 3.2: Characteristics of a family of CMOS gates

Gate type	Fan-in	Propagation delays		Load factor [standard loads]	Size [equiv. gates]
		$t_{pLH}$ [ns]	$t_{pHL}$ [ns]		
AND	2	$0.15 + 0.037L$	$0.16 + 0.017L$	1.0	2
AND	3	$0.20 + 0.038L$	$0.18 + 0.018L$	1.0	2
AND	4	$0.28 + 0.039L$	$0.21 + 0.019L$	1.0	3
OR	2	$0.12 + 0.037L$	$0.20 + 0.019L$	1.0	2
OR	3	$0.12 + 0.038L$	$0.34 + 0.022L$	1.0	2
OR	4	$0.13 + 0.038L$	$0.45 + 0.025L$	1.0	3
NOT	1	$0.02 + 0.038L$	$0.05 + 0.017L$	1.0	1
NAND	2	$0.05 + 0.038L$	$0.08 + 0.027L$	1.0	1
NAND	3	$0.07 + 0.038L$	$0.09 + 0.039L$	1.0	2
NAND	4	$0.10 + 0.037L$	$0.12 + 0.051L$	1.0	2
NAND	5	$0.21 + 0.038L$	$0.34 + 0.019L$	1.0	4
NAND	6	$0.24 + 0.037L$	$0.36 + 0.019L$	1.0	5
NAND	8	$0.24 + 0.038L$	$0.42 + 0.019L$	1.0	6
NOR	2	$0.06 + 0.075L$	$0.07 + 0.016L$	1.0	1
NOR	3	$0.16 + 0.111L$	$0.08 + 0.017L$	1.0	2
NOR	4	$0.23 + 0.149L$	$0.08 + 0.017L$	1.0	4
NOR	5	$0.38 + 0.038L$	$0.23 + 0.018L$	1.0	4
NOR	6	$0.46 + 0.037L$	$0.24 + 0.018L$	1.0	5
NOR	8	$0.54 + 0.038L$	$0.23 + 0.018L$	1.0	6
XOR	2*	$0.30 + 0.036L$	$0.30 + 0.021L$	1.1	3
		$0.16 + 0.036L$	$0.15 + 0.020L$	2.0	
XOR	3*	$0.50 + 0.038L$	$0.49 + 0.027L$	1.1	6
		$0.28 + 0.039L$	$0.27 + 0.027L$	2.4	
		$0.19 + 0.036L$	$0.17 + 0.025L$	2.1	
XNOR	2*	$0.30 + 0.036L$	$0.30 + 0.021L$	1.1	3
		$0.16 + 0.036L$	$0.15 + 0.020L$	2.0	
XNOR	3*	$0.50 + 0.038L$	$0.49 + 0.027L$	1.1	6
		$0.28 + 0.039L$	$0.27 + 0.027L$	2.3	
		$0.19 + 0.036L$	$0.17 + 0.025L$	1.3	
2-OR/NAND2	4	$0.17 + 0.075L$	$0.10 + 0.028L$	1.0	2
2-AND/NOR2	4	$0.17 + 0.075L$	$0.10 + 0.028L$	1.0	2

## LEVELS OF INTEGRATION

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Level of Integration	Technology	Number of transistors	Typical functions
SSI	bipolar	$\approx 10$	Individual gates, flip-flops
MSI	MOS, bipolar	10-100	Adders, counters, registers
LSI	MOS, bipolar	100-10,000	ROMs, PLAs, small memories
VLSI	MOS, bipolar	$> 10,000$	large memories, microprocessors, complex systems

# VLSI CIRCUIT-LEVEL DESIGN STYLES

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## FULL-CUSTOM

## SEMI-CUSTOM (standard cells)

## GATE-ARRAY

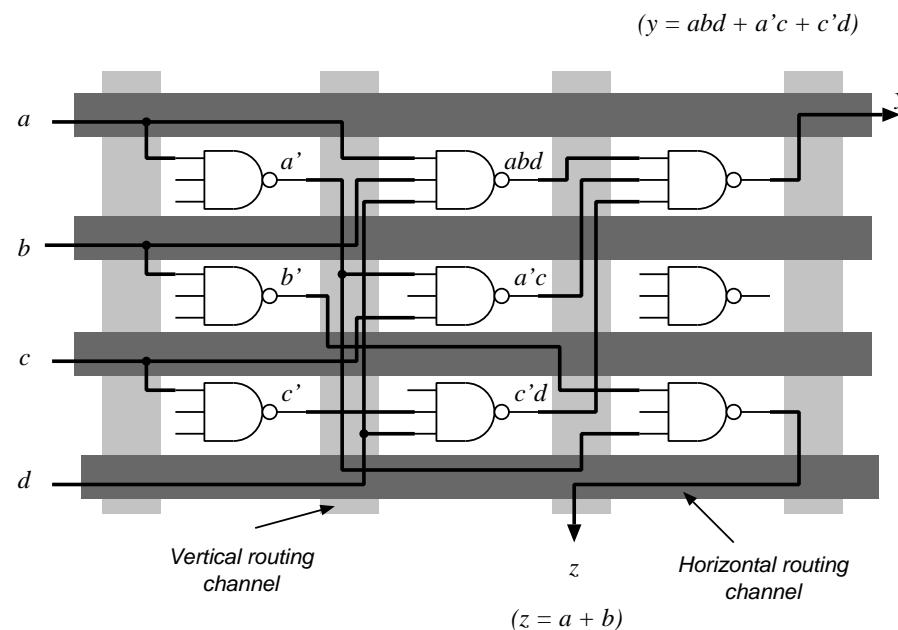


Figure 3.17: EXAMPLE OF GATE ARRAY.

## PACKAGING LEVEL: CHIPS, BOARDS, AND CABINETS

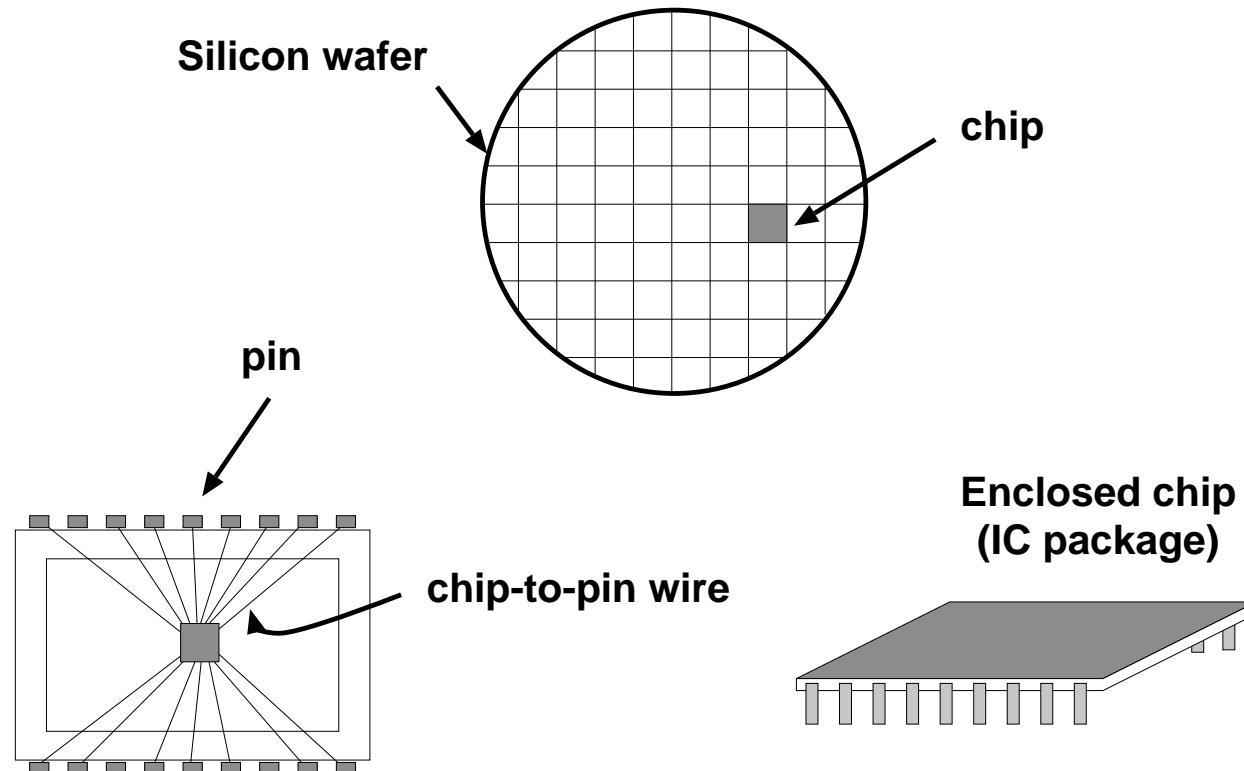


Figure 3.18: SILICON WAFER, CHIP AND INTEGRATED CIRCUIT PACKAGE

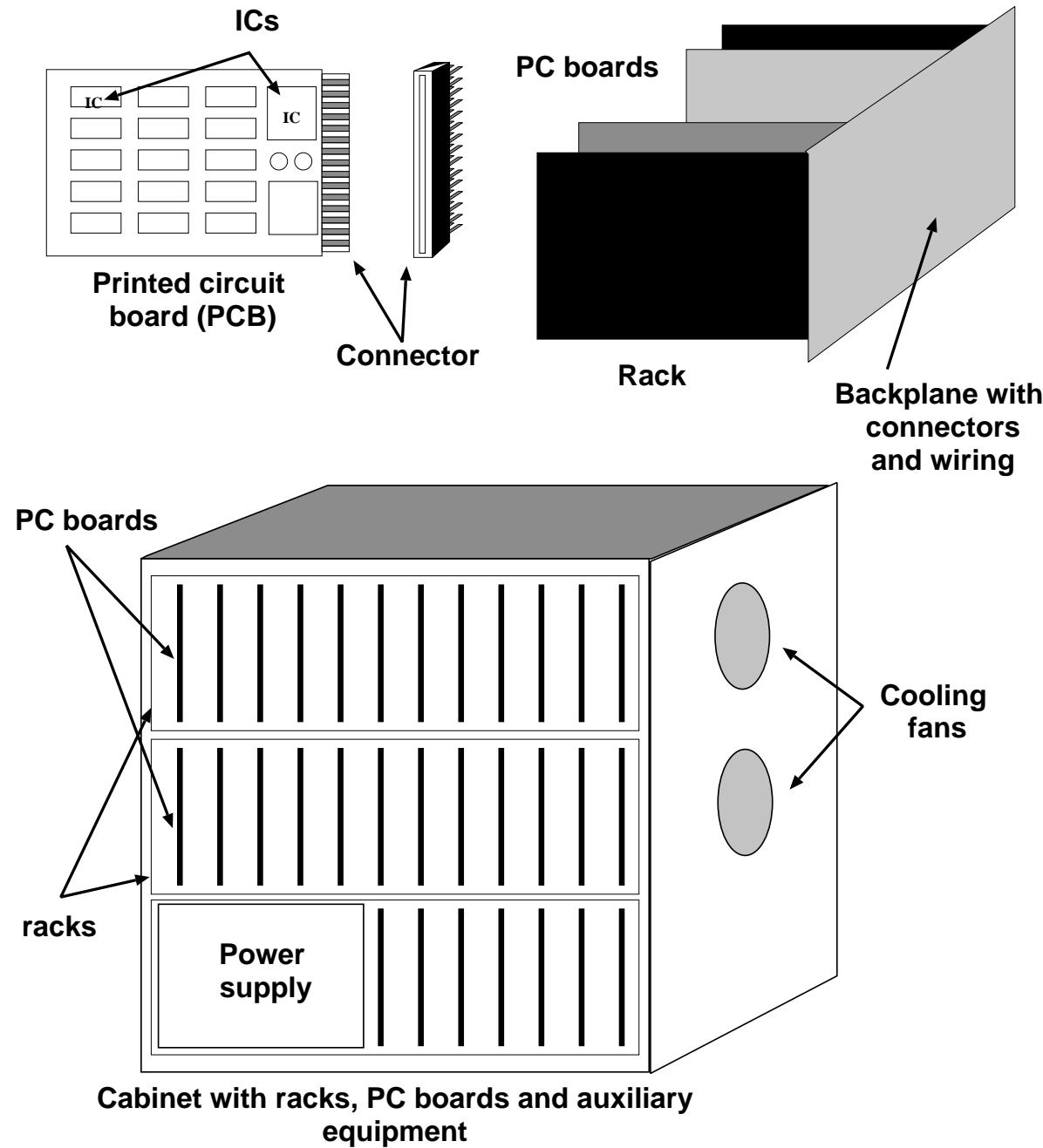


Figure 3.19: PACKAGING LEVELS

## PACKAGING LEVELS: EXAMPLE

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IBM 3081 central processing unit:

Level of Packaging	Number of Components	Size [mm × mm]
Module	100–133 chips	90 × 90
PC Board	6 – 9 modules	600 × 700
Subsystem (processor)	3 boards	
System (CPU)	2 subsystems	